SD9649 OVERVIEW

The SD9649 uses a multistage pipeline architecture to provide 14-bit accuracy at 65MSps data rates and to guarantee no missing codes over the full operating temperature range.

The SD9649 features internal references and can operate without an external reference or external common-mode bias.

Programming for configuration and control is accomplished using a 3-wire SPI-compatible interface. The digital output data can be programmed to be delivered in offset binary, gray code, or twos complement format. Further, to decrease EMI, the output data can be scrambled. A data output clock (DCO) is provided for each ADC channel to ensure proper timing at the receiver.

FEATURES

- SNR: 75.3dBFS at f_{IN} = 30.2MHz at f_{S} = 65MSps
- SFDR: 91.0dBc at f_{IN} = 30.2MHz at f_{S} = 65MSps
- -154.8dBFS/Hz input-noise at f_{IN} = 30.2MHz at f_{S} = 65MSps
- 2.0V_{p-p} nominal input
- Integer 1-to-8 input clock divider (520MHz maximum input)
- Sample rates of up to 65MSps
- 1.8V analog supply voltage
- Up to 3.3V digital I/O supply voltage
- · Internal ADC voltage reference
- · ADC clock duty cycle correction
- · Serial port control
- Energy saving power-down modes

VINP [D[13:0] ADC CMOS VINM L CLK+ DIV REG DCS SPI SCLK/DFS SDIO/PDWN **RBIAS** VREF SENSE MODE/OR \C<u>M</u>

Figure 1: SD9649 Functional Block Diagram.

APPLICATIONS

- · Communications
- · General-purpose software radios
- Data acquisition systems (DAQ)
- · Process control Systems
- · Smart antenna systems
- · Multimode digital receivers
- · Ultrasound equipment
- Radar/LiDAR applications
- · Test and Measurement



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SPECIFICATIONS

DC Specifications

At $T_A = 25$ °C, $V_{AVDD} = 1.8V$, $V_{DRVDD} = 1.8V$, $F_{CLK} = 65$ MHz, $A_{IN} = -1$ dBFS, differential AC-coupled sine wave external clock source, unless otherwise noted.

Table 1. DC Specifications.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
Resolution			14		bits
Accuracy					
No Missing Codes	Full		Guaranteed		
Offset Error	Full	-0.50		0.50	%FSR
Gain Error	Full		1.50		%FSR
DNL	Full			±1.2	LSB
INL	Full			±2.8	LSB
Matching					
Offset Error	25°C	-0.70		0.70	%FSR
Gain Error	25°C		0.75		%FSR
Temperature Drift					
Offset Error	Full		0.05		ppm/°C
Gain Error	Full		1.50		ppm/°C
Internal Voltage Reference					
Output Voltage	Full	0.99	1.02	1.05	V
External Voltage Reference					
Range	Full	0.90		1.05	V
Input Referred Noise					
$V_{REF} = 1.0V$	25°C		0.85		LSB(rms)
Analog Input					
Input Span, VREF = 1.0V	Full		2.0		V
Input Capacitance	Full		6.0		pF
Input Resistance	Full		2.0		kΩ
Input Common-Mode Voltage	Full		0.70		V
Input Common-Mode Range	Full	0.65		0.75	V
VCM Voltage	Full		0.70		V
VCM Current Capability	Full		100		μА
Reference Input Resistance	Full		50		kΩ
Power Supply					
V_{AVDD}	Full	1.7	1.8	1.9	V
V_{DRVDD}	Full	1.7	1.8	3.6	V
I _{AVDD} @1.8V	Full		167.0		mA
I _{DRVDD} @1.8V	Full		17.8		mA
Power Consumption					
Sine Wave Input	Full		334.6		mW
Standby ¹	Full		54.8		mW
Power Down	Full		8.0		mW

¹ Standby power is measured with a sinewave input and active clock.

AC Specifications

At $T_A = 25$ °C, $V_{AVDD} = 1.8V$, $V_{DRVDD} = 1.8V$, $F_{CLK} = 65MHz$, $A_{IN} = -1dBFS$, differential AC-coupled sine wave external clock source, unless otherwise noted.

Table 2. AC Specifications.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
Signal-to-Noise Ratio (SNR)					
f _{IN} = 6.55MHz	25°C		75.5		dBFS
f _{IN} = 30.2MHz	25°C	74.8	75.3		dBFS
	Full	74.6			dBFS
f _{IN} = 70.2MHz	25°C		74.4		dBFS
f _{IN} = 220MHz	25°C		69.5		dBFS
Signal-to-Noise and Distortion Ratio (SNDR)					
f _{IN} = 6.55MHz	25°C		75.2		dBFS
f _{IN} = 30.2MHz	25°C	74.5	75.0		dBFS
	Full	74.0			dBFS
f _{IN} = 70.2MHz	25°C		74.1		dBFS
f _{IN} = 220MHz	25°C		67.7		dBFS
Effective Number of Bits (ENOB)					
f _{IN} = 6.55MHz	25°C		12.2		bits
f _{IN} = 30.2MHz	25°C		12.2		bits
f _{IN} = 70.2MHz	25°C		12.0		bits
f _{IN} = 220MHz	25°C		10.9		bits
Worst Harmonic Power					
f _{IN} = 6.55MHz	25°C		-93.0		dBc
f _{IN} = 30.2MHz	25°C		-91.0	-85.0	dBc
f _{IN} = 70.2MHz	25°C		-89.0		dBc
f _{IN} = 220MHz	25°C		-72.0		dBc
Worst non-Harmonic Power					
f _{IN} = 6.55MHz	25°C		-95.0		dBc
f _{IN} = 30.2MHz	25°C		-94.0	-88.0	dBc
f _{IN} = 70.2MHz	25°C		-89.0		dBc
f _{IN} = 220MHz	25°C		-79.0		dBc
Spurious-Free Dynamic Range¹ (SFDR)					
$f_{IN} = 6.55MHz$	25°C		93.0		dBc
f _{IN} = 30.2MHz	25°C	85.0	91.0		dBc
	Full	84.0			dBc
f _{IN} = 70.2MHz	25°C		89.0		dBc
f _{IN} = 220MHz	25°C		72.0		dBc
Two-Tone SFDR					
f _{IN1} = 29.1MHz, f _{IN2} = 30.6MHz	25°C		89.1		MHz
Analog Input Bandwidth	Full		650.0		MHz

 $^{^{\}rm 1}\,\text{SFDR}$ excludes the DC and $f_{\rm s}/2$ bins.

Digital Specification

 V_{AVDD} = 1.8V, V_{DRVDD} = 1.8V, F_{CLK} = 65MHz, A_{IN} = -1dBFS, differential AC-coupled sine wave external clock source, DCS enabled, unless otherwise noted.

Table 3. Differential Clock Input.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
Logic Compliance	Full	СМО	S/LVDS/LVF	PECL	
Internal Common-Mode Bias	Full		0.9		V
Differential Input Voltage	Full	0.3		3.6	V_{p-p}
Input Voltage Range	Full	V _{AGND} -0.3		V _{AVDD} +0.2	V
Input Common-Mode Range	Full	0.75		1.05	V
High Level Input Current	Full	-10		10	μΑ
Low Level Input Current	Full	-10		10	μΑ
Input Capacitance	Full		1.7		pF
Input Resistance	Full		6		kΩ

Table 4. CSB Input.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
High Level Input Voltage	Full	1.22			V
Low Level Input Voltage	Full			0.6	V
High Level Input Current	Full	-1		1	μΑ
Low Level Input Current	Full	-1		1	μΑ
Input Capacitance	Full		1.5		pF
Input Resistance	Full		15		kΩ

Table 5. SCLK/DFS Input.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
High Level Input Voltage	Full	1.22			V
Low Level Input Voltage	Full			0.6	V
High Level Input Current	Full	-1		1	μΑ
Low Level Input Current	Full	-1		1	μΑ
Input Capacitance	Full		1.5		pF
Input Resistance	Full		15		kΩ

Table 6. SDIO/PDWN Input.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
High Level Input Voltage	Full	1.22			V
Low Level Input Voltage	Full			0.6	V
High Level Input Current	Full	-1		1	μΑ
Low Level Input Current	Full	-1		1	μΑ
Input Capacitance	Full		1.5		pF
Input Resistance	Full		15		kΩ

Table 7. CMOS Outputs (DATA and OR).

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
DRVDD = 3.3V					
High Level Output Voltage @50μΑ	Full	3.2			V
High Level Output Voltage @0.5mA	Full	3.1			V
Low Level Output Voltage @50µA	Full			0.05	V
Low Level Output Voltage @1.6mA	Full			0.1	V
DRVDD = 1.8V					
High Level Output Voltage @50µA	Full	1.75			V
High Level Output Voltage @0.5mA	Full	1.7			V
Low Level Output Voltage @50µA	Full			0.05	V
Low Level Output Voltage @1.6mA	Full			0.2	V

Switching Specifications

 V_{AVDD} = 1.8V, V_{DRVDD} = 1.8V, F_{CLK} = 65MHz, A_{IN} = -1dBFS, differential AC-coupled sine wave external clock source, DCS enabled, unless otherwise noted.

Table 8. Clock Input Timing.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
Input Clock Rate	Full			520.0	MHz
Conversion Rate (after clock divider)	Full	3.0		65.0	MHz
CLK Pulse Width High (t _{CH})					
Divide-by-1 Mode, DCS Enabled	Full	1.5			ns
Divide-by-1 Mode, DCS Disabled	Full	6.9	7.7	8.5	ns
Divide-by-2 Mode Through Divide-by-8 Mode	Full	1.0			ns
Aperture Delay (t _A)	Full		0.5		ns
Aperture Uncertainty (Jitter, t _J)	Full		140.0		fs

Table 9. Data Output.

PARAMETER	TEMP	MIN	TYP	MAX	UNIT
CMOS Mode					
Data Propagation Delay (t _{PD})	Full		5.5		ns
DCO Propagation Delay (t _{DCO})	Full		6.5		ns
DCO to Data Skew (t _{SKEW})	Full		-1.0		ns
Pipeline Delay (Latency, L)	Full		35		Cycles
Wake-Up Time (from sleep)	Full		5		μs
Wake-Up Time (from power down)	Full		500.0		μs
Out-of-Range Recovery Time	Full		3		Cycles

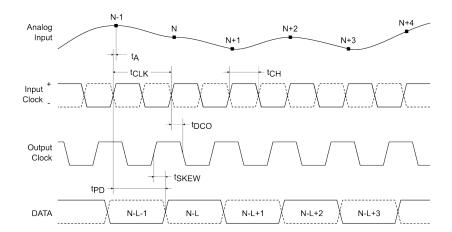


Figure 2: Parallel CMOS Output Mode Timing.

ABSOLUTE MAXIMUM RATINGS

Table 10. Absolute Maximum Ratings ($T_A = 25$ °C, unless otherwise specified).

Parameter	Symbol	Conditions	Min	Max	Units
AVDD	V_{AVDD}	Relative to AGND	-0.3	2.0	V
DRVDD	V_{DRVDD}	Relative to AGND	-0.3	3.8	V
VINP, VINM		Relative to AGND	-0.3	2.0	V
CLK+, CLK-		Relative to AGND	-0.3	2.0	V
RBIAS		Relative to AGND	-0.3	2.0	V
SENSE		Relative to AGND	-0.3	2.0	V
VCM		Relative to AGND	-0.3	2.0	V
VREF		Relative to AGND	-0.3	2.0	V
CSB		Relative to AGND	-0.3	3.8	V
SCLK/DFS		Relative to AGND	-0.3	3.8	V
SDIO/PDWN		Relative to AGND	-0.3	3.8	V
MODE/OR		Relative to AGND	-0.3	3.8	V
D0,, D13		Relative to AGND	-0.3	3.8	V
DCO		Relative to AGND	-0.3	3.8	V
Operating Temperature Range (Ambient)			-40	85	
Maximum Junction Temperature Under Bias				125	°C
Storage Temperature Range (Ambient)			-65	150	

Notes:

Stresses beyond those listed under Table 10 may cause permanent damage to the device. These are stress ratings only
and functional operation of the device at these or any other conditions beyond those indicated under recommended
operating conditions is not implied. Exposure to absolute—maximum—rated conditions for extended periods may affect
device reliability.

ESD CAUTION.



Electrostatic Discharge Sensitive Device.

Proper ESD precautions should be observed to prevent performance degradation or loss of functionality.

PACKAGE

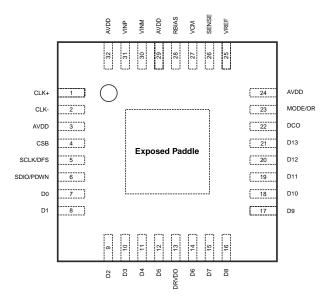


Figure 3: SD9649 Package Top View.

- 1. NC = No Connect.
- 2. The exposed thermal pad on the bottom of the package provides the analog ground for the part and must be connected for proper operation.

Table 11. Pin Descriptions.

Number	Name	Туре	Comment
0	AGND	Ground	Exposed Paddle, Analog Ground.
1	CLK+	Input	ADC Clock Input (Plus).
2	CLK-	Input	ADC Clock Input (Minus).
3	AVDD	Power	Analog Power Supply (1.8 V Nominal).
4	CSB	Input	SPI Chip Select (Active Low).
5	SCLK/DFS	Input	SPI Serial Clock/Data Format Select Pin in External Pin Mode.
6	SDIO/PDWN	InOut	SPI Serial Data I/O. Power Down Pin in External Pin Mode.
7	D0	Output	Output Data 0.
8	D1	Output	Output Data 1.
9	D2	Output	Output Data 2.
10	D3	Output	Output Data 3.
11	D4	Output	Output Data 4.
12	D5	Output	Output Data 5.
13	DRVDD	Power	Digital I/O Supply.
14	D6	Output	Output Data 6.
15	D7	Output	Output Data 7.
16	D8	Output	Output Data 8.
17	D9	Output	Output Data 9.
18	D10	Output	Output Data 10.
19	D11	Output	Output Data 11.
20	D12	Output	Output Data 12.

Number	Name	Туре	Comment	
21	D13	Output	Output Data 13.	
22	DCO	Output	Clock Output.	
23	MODE/OR	InOut	Chip Mode Select Input (MODE)/Out-of-Range Digital Output in SPI Mode (OR).	
24	AVDD	Power	Analog Power Supply (1.8 V Nominal).	
25	VREF	InOut	Voltage Reference Input/Output.	
26	SENSE	Input	Reference Programming Pin.	
27	VCM	Output	This pin outputs the common-mode voltage that can be used externally to bias the analog input pins.	
28	RBIAS	InOut	External Reference Bias Resistor. Connect to $30k\Omega$ (1% tolerance) resistor to ground.	
29	AVDD	Power	Analog Power Supply (1.8 V Nominal).	
30	VINM	Input	Differential Analog Input Pin (Minus).	
31	VINP	Input	Differential Analog Input Pin (Plus).	
32	AVDD	Power	Analog Power Supply (1.8 V Nominal).	

TYPYCAL PERFORMANCE CHARACTERISTICS

At $T_A = 25$ °C, $V_{AVDD} = 1.8V$, $V_{DRVDD} = 1.8V$, $F_{CLK} = 65$ MHz, $A_{IN} = -1$ dBFS, differential AC-coupled clock source, unless otherwise noted.

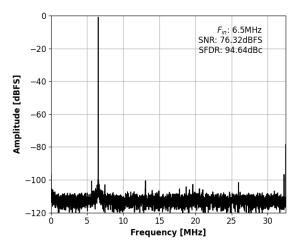


Figure 4: Single-Tone FFT with f_{IN} =6.55MHz.

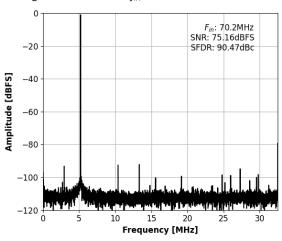


Figure 6: Single-Tone FFT with f_{IN} =70.2MHz.

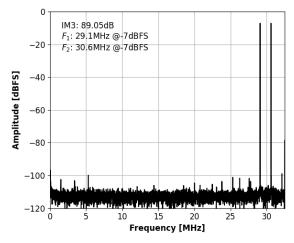


Figure 8: Two-Tone FFT with f_{IN1} =29.1MHz, f_{IN2} =30.6MHz.

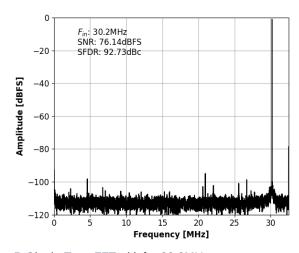


Figure 5: Single-Tone FFT with f_{IN} =30.2MHz.

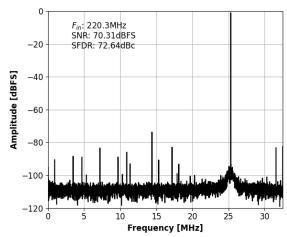


Figure 7: Single-Tone FFT with f_{IN} =220MHz.

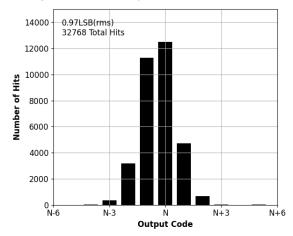


Figure 9: Grounded Input Histogram.

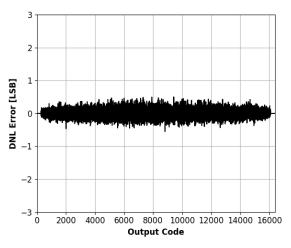


Figure 10: DNL Error with f_{IN} =6.55MHz.

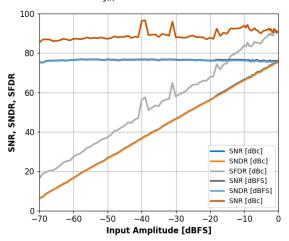


Figure 12: Single-Tone SNR, SNDR and SFDR vs. Input Amplitude Figure 13: Single-Tone SNR, SNDR and SFDR vs. Input with f_{IN} =30.2MHz.

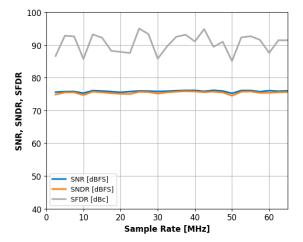


Figure 14: Single-Tone SNR, SNDR and SFDR vs. Sample Rate with f_{IN} =30.2MHz.

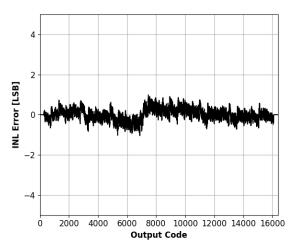
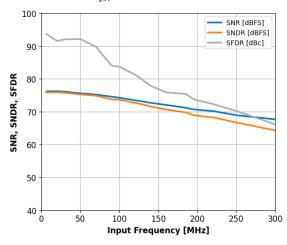
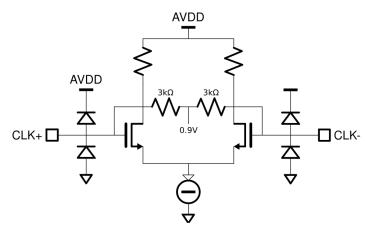


Figure 11: INL Error with f_{IN} =6.55MHz.



Frequency with f_s =65MHz.

EQUIVALENT CIRCUITS



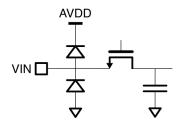


Figure 16: Equivalent Analog Input Circuit.

Figure 15: Equivalent Clock Input Circuit.

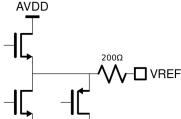
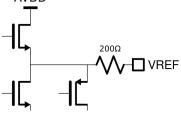


Figure 17: Equivalent VREF Circuit.



AVDD **√**/-□ ∨CM

Figure 18: Equivalent VCM Circuit.

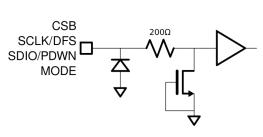


Figure 19: Equivalent CSB, SCLK/DFS, SDIO/PDWN or MODE Input Circuit.

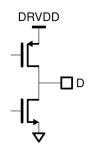


Figure 20: Equivalent Digital Output Circuit.

THEORY OF OPERATION

ADC Architecture

The ADC uses a pipelined architecture and innovative patented switched-capacitor circuits. The differential implementation makes it highly immune to power supply noise and reference voltage self-modulation.

Analog Input

The input stage behaves as a switched-capacitor network, presenting itself to the driving circuit as a combination of a switch and a sampling capacitor. The capacitor is reset prior to each conversion cycle, effectively eliminating non-linear memory effects commonly observed in some pipelined ADC architectures. The ADC does not include an internal commonmode bias therefore, the driving source must provide an appropriate common-mode voltage.

Differential Clock Input

The SD9649 features a differential clock receiver with an integrated common-mode bias. For proper operation, the clock inputs should be AC-coupled using 10nF capacitors.

Differential Clock Configuration. For optimal jitter performance, a differential clock source is recommended. Connect the differential clock signals to CLK+ and CLK- through 10nF AC-coupling capacitors.

Single-Ended Clock Configuration. If a single-ended clock source is used, AC-couple the signal to the CLK+ pin. In this configuration, connect a 10nF capacitor between the CLK- pin and analog ground to maintain proper biasing.

Clock Jitter Considerations. Clock jitter has a significant impact on the ADC's signal-to-noise ratio (SNR). The sensitivity to jitter increases with input signal frequency. For best performance, use a low-noise differential clock with fast edge transitions.

Note: In some conditions the part can enter in manufacturing test mode if both differential clock inputs are held low for more than 1ms. This behavior can be blocked by writing 1 to register *0x4cf*, bit[15].

Clock Divider

The ADC includes a programmable clock divider that allows the input clock to be divided by integer values from 2 to 8. The divider is configured by setting register 0x463, bits [7:5], to the desired division value. A value of 0 (default) bypasses the divider entirely.

By default, the divider starts asynchronously.

Clock Duty-Cycle Requirements. The ADC utilizes both the rising and falling edges of the input clock (or the divided clock, if the divider is enabled) for internal sampling operations. To achieve optimal performance — especially at the maximum sampling rate — the clock duty cycle should be as close to 50% as possible.

When the divider is enabled with an even divisor, a 50% duty cycle is guaranteed by design. If the application uses a clock with a non-ideal duty cycle, a Duty Cycle Stabilizer (DCS) can be enabled to improve performance.

ADC Self-Calibration

The ADC includes an automatic calibration mechanism that is executed at power-up to ensure optimal performance. For best results, calibration should be performed at the actual sampling rate used during operation. To support this, the device continuously monitors the sampling clock frequency and automatically re-triggers calibration if a significant change is detected. This feature can be disabled by setting bit[0] of the *0x4c9* register to 1.

Manual calibration can also be initiated by toggling *0xcc1*, bit[4] from 0 to 1. The calibration process is implemented using a state-machine architecture, ensuring a deterministic and predictable calibration time.

In addition, the ADC supports a Background Calibration (BGC) mode, which is disabled by default. BGC is beneficial in environments with large temperature variations near the extremes of the specified operating temperature range. When enabled, BGC injects a dither signal into the ADC input path, improving performance under thermal stress. However, this

dither consumes approximately 0.8dB of the ADC's input range, resulting in earlier clipping compared to when BGC is disabled.

To enable BGC, set the following bits to 1:

- 0xce1, bit[15]
- 0xce3, bit[3]

After enabling these bits, manually trigger calibration as described above.

Stand-by and Power-Down Modes

The SD9649 supports two power-saving modes that can be used when the ADC is not actively sampling. In both modes, the SPI interface (if enabled) remains operational.

Power-Down Mode. This mode disables most of the internal circuitry, resulting in the lowest residual supply current. It is ideal for applications requiring minimal power consumption during idle periods. Power-down mode can be enabled via:

- · The PDWN pin (when available), or
- Setting register 0x457, bit[7], to 1.

Standby Mode. Standby mode offers a faster wake-up time compared to power-down mode, at the cost of slightly higher residual current. It is suitable for applications that require rapid recovery from idle states. To enable standby mode, set register *0x457*, bits [3] and [8], to 1.

Note: It is recommended to disable the ADC auto-calibration when using standby mode to avoid unintended calibration cycles during transitions.

Pin Functions

The SD9649 offers several functions available via dual function pin controls (external pin mode vs. SPI mode). The SD9649 detects the SPI mode during the first SPI transaction after power-up. If the user does not want to program the device via the SPI interface, the dual function is available.

DFS

Data Format Select can be used to select between offset binary or two's complement when operating in the external pin mode.

RBIAS

External Reference Bias Resistor. The SD9649 requires a $30k\Omega$, 1% resistor, between pin RBIAS and AGND to set the default bias current for the ADC.

VCM

Common-Mode Level Bias Output for Analog Input. The VCM pin provides a DC voltage that can be used to bias the ADC input common-mode level, either directly using a passive circuit or indirectly as a common-mode reference voltage for the driving active device. In most use cases, the default common-mode voltage level is optimal.

VREF

The ADC supports both internal (default) and external voltage reference sources, selectable via the VREF pin. The selection between internal and external reference voltage can be made in one of two ways:

- Using the SENSE pin: a logic high level selects the external reference.
- Via register control: setting register 0x45d, bit[5] to 1 selects the external reference.

Internal Reference Output. When the internal voltage reference is used, the VREF pin can function as a reference output.

This output can be enabled by setting register 0x45d, bits [11:10], to 0x3.

If the SENSE pin is held low, the reference output is enabled by default. To disable the reference output in this configuration, set register 0x45d, bits [11:10], to 0x2.

SERIAL PORT INTERFACE

The SD9649 uses a 3-wire Serial Port Interface (SPI) that gives the user flexibility to configure the converter for specific functions, depending on the application, through a register space provided inside the ADC.

The interface signals are:

- SCLK defines the bit rate at which serial data is driven onto, and sampled from, the bus;
- CSB defines the boundaries of a basic data 'unit', comprised of multiple serial bits;
- · SDIO is the serial data IO wire;

The read and write cycles are described in the figure below. The complete instruction cycle is 32-bits long. The falling edge of CSB combines with the rising edge of SCLK marks the start of the instruction cycle. The address space is 13 bits long (A<12:0>) and the data is 16 bits wide (D<15:0>).

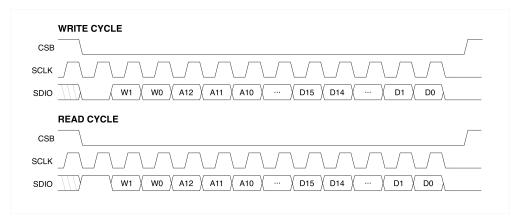


Figure 21: 3-wire SPI timing.

Table 12. SPI Timing.

PARAMETER	SYMBOL	MIN	TYP	MAX	UNIT
Setup time between the data and the rising edge of SCLK	t _{DS}	2			ns
Hold time between the data and the rising edge of SCLK	t _{HD}	2			ns
Period of the SCLK	t _{sclk}	40			ns
Setup time between CSB and SCLK	t _{s,csb-sclk}	2			ns
Hold time between CSB and SCLK	t _{H,CSB-SCLK}	2			ns
Minimum period that SCLK should be in a logic high state	t _{SCLK,high}	10			ns
Minimum period that SCLK should be in a logic low state	t _{SCLK,low}	10			ns
Time required for the SDIO pin to switch from an input to an output relative to the SCLK falling edge	$t_{\text{SDIO},\text{EN}}$	10			ns
Time required for the SDIO pin to switch from an output to an input relative to the SCLK rising edge	t _{sDIO,DIS}	10			ns

The falling edge of CSB, in conjunction with the rising edge of SCLK, determines the start of the framing.

Two bits, W1 and W0, determine how many bytes of data that can be transferred in the same write cycle (see Table 13). If more than 16 bits (2 Bytes) of data are being transferred the address is increased sequentially.

Table 13. SPI Word Length.

[W1,W0]	Data length
00	Not supported
01	Two bytes of data can be transferred
10	Not supported
11	Four bytes of data can be transferred

The SPI pins should not be active when the full dynamic performance of the ADC is required. Noise from SCLK, CSB and the data transactions can degrade ADC performance.

OUTPUT MODE

Data Scrambler

Interference originating from the digital outputs of the ADC can be difficult to eliminate entirely. Such interference may result from capacitive or inductive coupling mechanisms, or from shared impedance paths in the ground plane. Even minimal coupling coefficients can introduce deterministic spurious tones into the ADC's output frequency spectrum. To mitigate this, digital output scrambling techniques can be employed prior to off-chip transmission. By randomizing the bit patterns, the spectral energy of these spurs is dispersed, effectively reducing their peak amplitudes and minimizing their impact on signal integrity.

The SD9649 can apply an exclusive-OR logic operation between the LSB and all other data output bits, while the LSB, overflow and clock outputs are not affected.



When this function is used, the receiver must apply the same function to unscramble the received data.

The data scrambler is enabled by programming control register 0x4b5, bit[13].

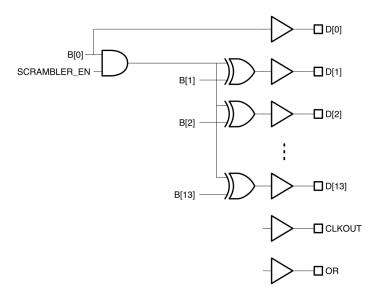


Figure 22: SD9649 Data Scrambler.

Alternate Bit Polarity

The alternate bit polarity is particularly effective to suppress digital feedback and minimize noise coupling on the PCB when the ADC input signal is near mid-scale and of very small amplitude. In this case, the digital output tends to toggle between patterns dominated by either logic high or logic low states. This synchronized switching of multiple bits can induce significant transient currents in the ground plane, leading to increased digital noise. This mode, when activated, inverts all odd-numbered data output bits prior to the output buffer stage while even-numbered bits, along with the overflow and clock output, remain unaffected thus ensuring that approximately half of the output bits transition are high while the other half transition are low. This balanced switching behavior helps cancel out opposing current flows in the ground return path, thereby reducing overall ground noise. At the receiving end, the original data can be reconstructed by inverting the same odd-numbered bits. This mode operates independently of the digital output randomization feature—both functions can be enabled or disabled separately. The Alternate Bit Polarity mode is configured via serial programming of control register *0x4b5*, bit[14].

Output Test Modes

The output test options are described in Table 14 and are selected via SPI programming at register 0x4b5, bits [5:2].

When an output test mode is enabled, the analog section of the ADC is disconnected from the digital back-end blocks and the test pattern is run through the output formatting block. These tests require an active input clock.

There are two pseudo-random number generators available, PN23 and PN9. The PN23 generator ($X^{23}+X^{18}+1$), selected by register 0x4b5, bits [5:2], set to 0x5, can be reset by setting register 0x4b5, bit [12], low; while the PN9 generator (X^9+X^5+1), selected by register 0x4b5 set to 0x6, can be reset by setting register 0x4b5, bit [11], low.

Table 14. Output Test Modes.

Mode	Function
0	Pass-Through
1	Midscale
2	+FS
3	-FS
4	Checkerboard
5	PN23
6	PN9
7	1/0 word toggle
8	User input
9	1/0 bit toggle
10	1x sync
11	1-bit high
12	Mixed frequency
13	Unused
14	Unused
15	Ramp

Pass-through and test patterns 1, 2, 3, 5 and 6 are subject to output formatting, while the other test modes are not. Test patterns 1, 8 and 15 can be applied to either one channel or both channels using 0x4b5, bit[7:6]. Patterns 4 and 7 can be toggled between the pattern and its inverse while test pattern 8 can be selected using registers 0x4bb, 0x4bd, [DB_TEST0_register] and [DB_TEST1_register].

CONTROL REGISTERS

The following tables describe the control registers. The tables describe the registers as follows:

Address: <hex value=""></hex>		RW or RO	Default: <hex value=""></hex>
bit field	default	field descript	ion.
	value		

where: **RW** indicates a Read/Write register and **RO** indicates a Read-Only register. If the register is read-only, the default value is omitted.

Registers not explicitly described in the following tables should not be written.



When changing control register values, read-modify-write procedure should be used. Some registers contain reserved bit fields for engineering purposes. This avoids inadvertently changing the values of those bits.

Address:	0x455	RW	Default: 0x1	
[0]	[0] 0x1 Soft reset		active low).	
		1	I	
Address:	0x457	RW	Default: 0x015	
[0]	0x1	Duty Cycle	Stabilizer enable.	
[1]	0x0	Duty Cycle	Stabilizer.	
[2]	0x1		utput enable (OE/OEB) control	
		0: Output		
		1: Output	depends on pin OE/OEB	
[3]	0x0	Output disa		
			depends on oeb_en_reg (default)	
		1: Disable	ed	
[4]	0x1	Reserved.		
[6:5]	0x0	Reserved.		
[7]	0x0	Software p	ower down.	
[8]	0x0	Software s	leep mode.	
Address:	0v//Ed	RW	Default: 0x0095	
		Reference		
[0]	0x1			
[4:1]	0xa	Reference		
[5]	0x0	Set reference.		
		0: Internal		
		1: External		
[9:6]	0x2	Reserved.		
[11:10]	0x0	Reserved.		
[14:12]	0x0	Reserved.		

Address:	0x463	RW	Default: 0x019		
[0]	0x1	Enable clock receiver.			
[2:1]	0x0	Clock RX common-mode bias.			
[4:3]	0x3	Clock RX b	Clock RX bias.		
[7:5]	0x0	Clock RX d	Clock RX divider control.		
		0: Bypass			
		1: Divide b			
		2: Divide l	oy 3		
		3:			
		7: Divide k	· F		
[8]	0x0		chip termination.		
[9]	0x0	Clock RX p	olarity.		
[10]	0x0	Reserved.			
Address:	Address: 0x465		Default: 0x0		
[2:0]	0x0		a interleaver.		
			rough, no interleaving		
	1: pass through, channels swapped, no interleaving		rough, channels swapped, no interleaving		
	2: N/A				
3: N/A					
4: Reserved					
		5: Reserve			
			dd interleaving		
		/: odd-eve	en interleaving		
Address:	0x473	RW	Default: 0x0000		
[4:0]	0x00	Reserved.			
[9:5]	0x00	Output data delay.			
[14:10]	0x00	Output clock delay.			
	I		•		
Address:	0x475	RW	Default: 0x1		
[0]	0x1	Enable VCI	И.		

Address:	0x4b5	RW	Default: 0x18c0		
[1:0]	0x0	Output form 0: Signed 1: Offset b 2: Gray co 3: N/A	binary pinary		
[5:2]	0x0	Output test	Output test mode select (see Table 14).		
[6]	0x1	Output test 0: Disable 1: Enable			
[7]	0x1	Reserved.			
[8]	0x0	Output test	toggle mode. Toggle between user test pattern 0 and 1.		
[10:9]	0x0		2'h2:		
[11]	0x1	PN9 genera	ator reset (active low)		
[12]	0x1	PN23 gene	rator reset (active low)		
[13]	0x0	Enable the	Enable the output data scrambler.		
[14]	0x0	Enable alte	rnate bit polarity switch.		
Address:	Address: 0x4b7		Default: 0x0092		
[15:0]	0x0092	PN9 initial s	seed.		
Address:	0x4b9	RW	Default: 0x3aff		
[15:0]	0x3aff	PN9 initial s	seed.		
Address:	0x4bb	RW	Default: 0x0000		
[15:0]	0x0000	User test pa	attern 0.		
Address:	0x4bd	RW	Default: 0x0000		
[15:0]	0x0000	User test pattern 1.			
Address: 0x4c9		RW	Default: 0x0000		
[0]	0x0	Disable aut	o-recalibration.		
[15:1]	0x0000	Reserved.			
Address:	1	RW	Default: 0x0035		
[14:0]	0x0035	Reserved.			
[15]	0x0035	Disable tes	t mode.		

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Address:	0x4fd	RO	Default: N/A	
[2:0]		Chip revision		
[6:3]		Label ID.		
[7]		Reserved.		
[8]		Reserved.		
[10:9]		Resolution ID for device 0: 10-bit 1: 12-bit 2: 14-bit 3: 16-bit		
[13:11]		Speed ID for	device.	
Address:	0x4ff	RO	Default: N/A	
[0]		Reserved.		
[1]		Analog Supp	ly Ready.	
[2]		Digital Supply	y Ready.	
[3]		I/O Supply Re	eady.	
[4]		Sense pin sta	atus.	
[5]		SPI enabled.		
[6]		Reserved.		
[7]		Reserved.		
[8]		Reserved.		
[9]		Reserved.		
[10]		Reserved.		
Address: (nvf02	RW	Default: 0x7f8	
[0]	0x0	Enable top le		
[1]	0x0		skew control DAC.	
[2]	0x0	Reserved.	Show solition by to.	
[3]	0x1	Reserved.		
[4]	0x1	Reserved.		
[10:5]	0x3f	Mask for ena	ble pin.	
	1	1	•	
Address:	0xf05	RW	Default: 0x30	
[5:0]	0x30	Mask for slee	ep pin.	
[6]	[6] 0x0 Sleep ADC			
[7]	[7] 0x0			
Address: 0xf07		RW	Default: 0x40	
[0]	0x0	Enable prima	ary clock.	
[1]	0x0	Analog clock	enable.	
[2]	0x0	ADC top leve	el clock divider.	
[3]	0x0	Reserved.		
راحا				
[4]	0x0	Reserved.		
	0x0 0x0	Reserved.		
[4]		Reserved.	enerator reset.	

Address:	0xf0b	RW	Default: 0x24
[2:0]	0x4	Clock rece	iver bias.
[5:3]	0x4	ADC maste	er bias.
Address:	0xf0f	RW	Default: 0x28
[1:0]	0x0	Clock divid	ler.
[3:2]	0x2	Clock dela	у.
[5:4]	0x2	Reserved.	
Address:	0xf11	RW	Default: 0x0b
[2:0]	0x3	Main bias.	
[4:3]	0x1	Input comr	mon mode level.
Address:	0xf27	RW	Default: 0x04
[5:0]	0x04	Dither enal	ble.
Address:	0xdc1	RW	Default: 0xbfff
[0]	0x1	Enable.	
[1]	0x1	Clock enal	ple.
[2]	0x1	Soft reset.	
[3]	0x1	Reserved.	
[4]	0x1	Calibration soft reset.	
[5]	0x1	Reserved.	
[6]	0x1	Reserved.	
[10:7]	0xf	Enable ma	sk for en_adc pin.
[15:11]	0x17	Sleep mas	k for sleep pin.
Address:	0xdc3	RW	Default: 0x0000
[3:0]	0x0	Clock phas	Se.
[11:4]	0x00	Clock fine	delay.
[12]	0x0	Enable fine	e delay register control.
[13]	0x0	Input clock	polarity switch.
[14]	0x0	Output clo	ck polarity switch.
Address:	0xde1	RW	Default: 0xbb28
[7:0]	0x28	Calibration length.	
[8]	0x1	Enable calibration.	
[9]	0x1	Foreground calibration.	
[14:10]	0x0	Reserved.	
[15]	0x1	Enable reta	ain mode.
Address:	0xde3	RW	Default: 0x8
[2:0]	0x0	Reserved.	•
[3]	0x1	Enable sta	ge calibration.

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Address: ()xcc1	RW	Default: 0xbfff
[0]	0x1	Enable.	
[1]	0x1	Clock enable	9.
[2]	0x1	Soft reset.	
[3]	0x1	Reserved.	
[4]	0x1	Calibration s	oft reset.
[5]	0x1	Reserved.	
[6]	0x1	Reserved.	
[10:7]	0xf	Enable masl	k for en_adc pin.
[15:11]	0x17	Sleep mask	for sleep pin.
		1	
Address: 0		RW	Default: 0x0000
[3:0]	0x0	Clock phase	
[11:4]	0x00	Clock fine delay.	
[12]	0x0	Enable fine delay register control.	
[13]	0x0	Input clock p	polarity switch.
[14]	0x0	Output clock polarity switch.	
		1	1
Address: 0)xce1	RW	Default: 0xbb28
[7:0]	0x28	Calibration le	-
[8]	0x1	Enable calib	
[9]	0x1	Foreground	calibration.
[14:10]	0x0	Reserved.	
[15]	0x1	Enable retain mode.	
		1	
Address: 0)xce3	RW	Default: 0x8
[2:0]	0x0	Reserved.	
[3]	0x1	Enable stage calibration.	



ORDERING INFORMATION

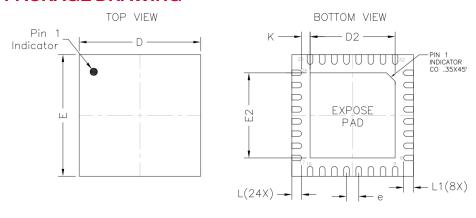
Base Part No.	Orderable Part No. Full Tray	Orderable Part No. Tray with 50Pcs	Orderable Part No. Reel with 750pcs
SD9649-65	SD9649-65-A-QA5-TC	SD9649-65-A-QA5-TA	SD9649-65-A-QA5-RD

EVK	Part No.
CMOS	SDE9649-C

This product is protected by several U.S. Patents (www.silannasemi.com/patents).

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PACKAGE DRAWING



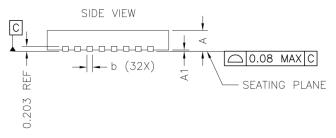


Figure 23: Package Dimensions.

DIMENSION TABLE				
SYMBOL	MINIMUM	NOMINAL	MAXIMUM	
A	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
b	0.20	0.25	0.30	
D	4.90	5.00	5.10	
D2	3.45	3.50	3.55	
E	4.90	5.00	5.10	
E2	3.45	3.50	3.55	
е	0.50 BSC			
L	0.35	0.40	0.45	
L1	0.33	0.38	0.43	
K	0.20	_	_	
N	32			

- NOTE:

 1. Reference Doc: GRT Doc;:JI-1032-001-24 REV 24 QTY:16/17
 Package Type: JEDEC OUTLINE-MO-220, Pack. Code WQFN(X532)
 PAD SIZE:B154X15*MIL
 2. Dimensioning and tolerancing conform to ASME Y14.5-2009.
 3. Ill
 3. Ill
 4. N is the foot an in millimeters.
 4. N is the foot another of terminals.
 5. Unilateral coplanarity zone applies to the exposed part as well as the terminals.
 6. Lead Finish: 100% Sn.

REVISION HISTORY

Version	Date	Comment
1.0	June 19, 2025	Initial Release.
2.0	July 30, 2025	Filled missing specifications. Changed RBIAS resistor to $30k\Omega$. Improved timing diagrams. Fixed typos.

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